Amendments to the Specification:

Please amend the specification as follows:

Please replace paragraph starting at page 17, line 9, with the following rewritten paragraph:

Figs. 4A and 4B are views each showing an example of a Hartmann image. Fig. 4A shows a case where measurement is performed using the second measurement part 25B with the short focal point or the low sensitivity or the high density, and each spot exists in the range ~~of a Hartmann lattice~~ smaller than a conversion pitch of the second conversion member 22B; i.e., in the range of the Hartmann lattice of the Hartmann plate. On the other hand, Fig. 4B shows a case where measurement is performed using the first measurement part 25A with the long focal point or the high sensitivity, and there is a case where a spot exists outside the range of the Hartmann lattice.

Please replace paragraph starting at page 17, line 18 and ending on page 18, line 12, with the following rewritten paragraph:

Figs. 5A and 5B are explanatory views of the measurement with the short focal point and the long focal point. In Fig. 5A, since the measurement is performed with the short focal point or the low sensitivity or the high density, the deviation of a spot position is small, and it is within the range ~~of the Hartmann lattice~~ smaller than a conversion pitch of the second conversion member 22B; i.e., in the range of the Hartmann lattice of the Hartmann plate. Accordingly, it is easy to bring the respective spots into correspondence with the lattice points. Besides, a defective position of the spot images can be easily detected, or the detection ranges of the respective spot images do not overlap and can be uniformly detected. On the other hand, in Fig. 5B, since the measurement is performed using the first measurement part 25A with the long focal point or the high sensitivity, the deviation of the spot position is large, and the spot can exist outside the range of the Hartmann lattice. Accordingly, when the spot position is deviated very largely, there is a case where it is difficult to bring the respective spots into correspondence with the lattice points. Besides, it is very difficult to recognize a defective position of the spot images. Then, in this embodiment, as shown in

Fig. 5C, the measurement is performed with the short focal point or the low sensitivity or the high density, and as a result, since a movement direction and a movement amount are known in some degree, in the case where the measurement is performed with the long focal point or the high sensitivity, the results are used to make it easy to bring the respective spots into correspondence with the lattice points.